

# NBSG11

## 2.5V/3.3V SiGe 1:2 Differential Clock Driver with RSECL\* Outputs

\*Reduced Swing ECL

### Description

The NBSG11 is a 1-to-2 differential fanout buffer, optimized for low skew and Ultra-Low JITTER.

Inputs incorporate internal 50 Ω termination resistors and accept Negative ECL (NECL), Positive ECL (PECL), CML, LVCMOS, LVTTTL, or LVDS. Outputs are Reduced Swing ECL (RSECL), 400 mV. All outputs loaded with 50 Ω to  $V_{CC} - 1.5$  V for BGA package and  $V_{CC} - 2$  V for QFN package.

### Features

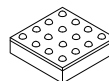
- Maximum Input Clock Frequency up to 12 GHz Typical
- Maximum Input Data Rate up to 12 Gb/s Typical
- 30 ps Typical Rise and Fall Times
- 125 ps Typical Propagation Delay
- RSPECL Output with Operating Range:  $V_{CC} = 2.375$  V to 3.465 V with  $V_{EE} = 0$  V
- RSNECL Output with RSNECL or NECL Inputs with Operating Range:  $V_{CC} = 0$  V with  $V_{EE} = -2.375$  V to  $-3.465$  V
- RSECL Output Level (400 mV Peak-to-Peak Output), Differential Output Only
- 50 Ω Internal Input Termination Resistors
- Compatible with Existing 2.5 V/3.3 V LVEP, EP, and LVEL Devices
- Pb-Free Packages are Available



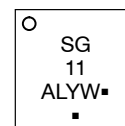
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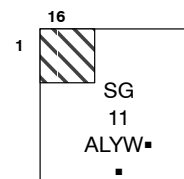
### MARKING DIAGRAMS\*



FCBGA-16  
BA SUFFIX  
CASE 489



QFN-16  
MN SUFFIX  
CASE 485G



A = Assembly Location  
L = Wafer Lot  
Y = Year  
W = Work Week  
▪ = Pb-Free Package

(Note: Microdot may be in either location)

\*For additional marking information, refer to Application Note AND8002/D.

### ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 10 of this data sheet.

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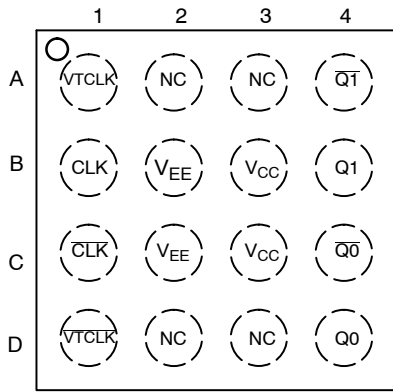


Figure 1. BGA-16 Pinout (Top View)

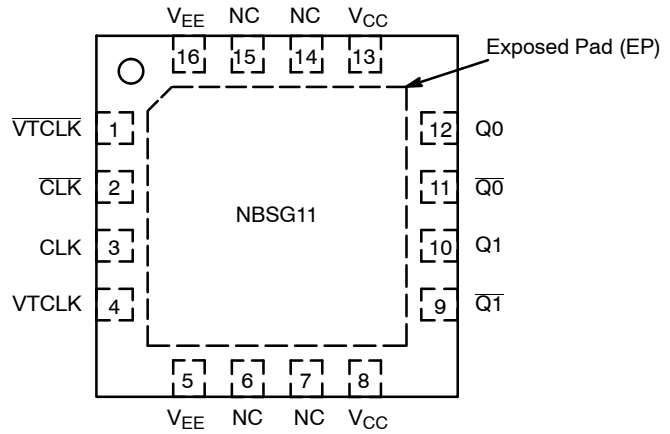


Figure 2. QFN-16 Pinout (Top View)

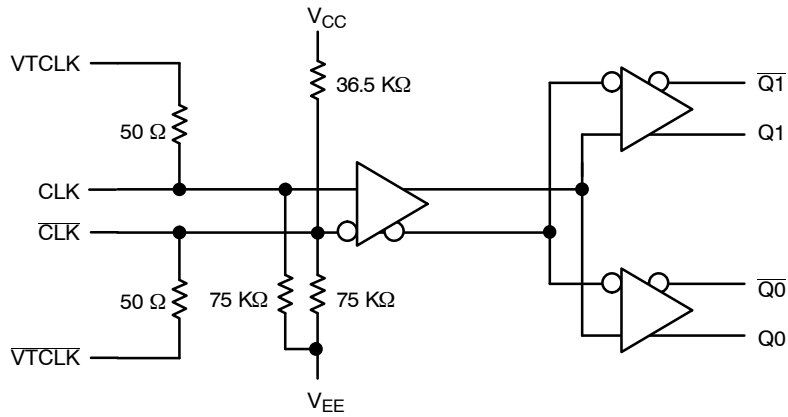
Table 1. PIN DESCRIPTION

Pin		Name	I/O	Description
BGA	QFN			
D1	1	VTCLK	-	Internal 50 Ω Termination Pin. See Table 2.
C1	2	CLK	ECL, CML, LVCMOS, LVDS, LVTTTL Input	Inverted Differential Input. Internal 75 kΩ to V <sub>EE</sub> and 36.5 kΩ to V <sub>CC</sub> .
B1	3	CLK	ECL, CML, LVCMOS, LVDS, LVTTTL Input	Noninverted Differential Input. Internal 75 kΩ to V <sub>EE</sub> .
A1	4	VTCLK	-	Internal 50 Ω Termination Pin. See Table 2.
B2,C2	5,16	V <sub>EE</sub>	-	Negative Supply Voltage
A2,A3,D2,D3	6,7,14,15	NC	-	No Connect
B3,C3	8,13	V <sub>CC</sub>	-	Positive Supply Voltage
A4	9	Q <sub>1</sub>	RSECL Output	Inverted Differential Output 1. Typically Terminated with 50 Ω to V <sub>TT</sub> = V <sub>CC</sub> - 2.0 V*.
B4	10	Q <sub>0</sub>	RSECL Output	Noninverted Differential Output 1. Typically Terminated with 50 Ω to V <sub>TT</sub> = V <sub>CC</sub> - 2.0 V*.
C4	11	Q <sub>0</sub>	RSECL Output	Inverted Differential output 0. Typically Terminated with 50 Ω to V <sub>TT</sub> = V <sub>CC</sub> - 2.0 V*.
D4	12	Q <sub>0</sub>	RSECL Output	Noninverted Differential Output 0. Typically Terminated with 50 Ω to V <sub>TT</sub> = V <sub>CC</sub> - 2.0 V*.
N/A	-	EP	-	The Exposed Pad (EP) and the QFN-16 package bottom is thermally connected to the die for improved heat transfer out of package. The exposed pad must be attached to a heat-sinking conduit. The pad is not electrically connected to the die but may be electrically and thermally connected to V <sub>EE</sub> on the PC board.

\*Devices in BGA package typically terminated with 50 Ω to V<sub>TT</sub> = V<sub>CC</sub> - 1.5 V.

1. The NC pins are electrically connected to the die and must be left open.
2. All V<sub>CC</sub> and V<sub>EE</sub> pins must be externally connected to Power Supply to guarantee proper operation. The thermally exposed pad on package bottom (see case drawing) must be attached to a heat-sinking conduit.
3. In the differential configuration when the input termination pins (VTCLK, VTCLK) are connected to a common termination voltage, and if no signal is applied then the device will be susceptible to self-oscillation.

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**Figure 3. Logic Diagram**

**Table 2. INTERFACING OPTIONS**

INTERFACING OPTIONS	CONNECTIONS
CML	Connect VTCLK and VTCLK to V <sub>CC</sub>
LVDS	Connect VTCLK and VTCLK together
AC-COUPLED	Bias VTCLK and VTCLK Inputs within (VIHCMR) Common Mode Range
RSECL, PECL, NECL	Standard ECL Termination Techniques
LVTTTL, LVCMOS	An external voltage should be applied to the unused complementary differential input. Nominal voltage is 1.5 V for LVTTTL and V <sub>CC</sub> /2 for LVCMOS inputs.

**Table 3. ATTRIBUTES**

Characteristics		Value	
Internal Input Pulldown Resistor (CLK, CLK-bar)		75 kΩ	
Internal Input Pullup Resistor (CLK-bar)		36.5 kΩ	
ESD Protection		Human Body Model	> 2 kV
		Machine Model	> 100 V
Moisture Sensitivity (Note 4)		Pb Pkg	Pb-Free Pkg
		FCBGA-16	Level 3
		QFN-16	Level 1
Flammability Rating		Oxygen Index: 28 to 34	
		UL 94 V-0 @ 0.125 in	
Transistor Count		125	
Meets or exceeds JEDEC Spec EIA/JESD78 IC Latchup Test			

4. For additional information, see Application Note AND8003/D.

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**Table 4. MAXIMUM RATINGS**

Symbol	Parameter	Condition 1	Condition 2	Rating	Unit
$V_{CC}$	Positive Power Supply	$V_{EE} = 0\text{ V}$		3.6	V
$V_{EE}$	Negative Power Supply	$V_{CC} = 0\text{ V}$		-3.6	V
$V_I$	Positive Input Negative Input	$V_{EE} = 0\text{ V}$ $V_{CC} = 0\text{ V}$	$V_I \leq V_{CC}$ $V_I \geq V_{EE}$	3.6 -3.6	V V
$V_{INPP}$	Differential Input Voltage $ D - \bar{D} $	$V_{CC} - V_{EE} \geq 2.8\text{ V}$ $V_{CC} - V_{EE} < 2.8\text{ V}$		2.8 $ V_{CC} - V_{EE} $	V V
$I_{out}$	Output Current	Continuous Surge		25 50	mA mA
$T_A$	Operating Temperature Range	FCBGA-16 QFN-16		-40 to +70 -40 to +85	°C
$T_{stg}$	Storage Temperature Range			-65 to +150	°C
$\theta_{JA}$	Thermal Resistance (Junction-to-Ambient) (Note 5)	0 lfpm 500 lfpm 0 lfpm 500 lfpm	FCBGA-16 FCBGA-16 QFN-16 QFN-16	108 86 41.6 35.2	°C/W °C/W °C/W °C/W
$\theta_{JC}$	Thermal Resistance (Junction-to-Case)	1S2P (Note 5) 2S2P (Note 6)	FCBGA-16 QFN-16	5.0 4.0	°C/W °C/W
$T_{sol}$	Wave Solder Pb Pb-Free			225 265	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

5. JEDEC standard multilayer board – 1S2P (1 signal, 2 power).

6. JEDEC standard multilayer board – 2S2P (2 signal, 2 power) with 8 filled thermal vias under exposed pad.

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**Table 5. DC CHARACTERISTICS, INPUT WITH RSPECL OUTPUT**  $V_{CC} = 2.5\text{ V}$ ;  $V_{EE} = 0\text{ V}$  (Note 7)

Symbol	Characteristic	-40°C			25°C			70°C(BGA)/85°C(QFN)**			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
$I_{EE}$	Negative Power Supply Current	45	60	75	45	60	75	45	60	75	mA
$V_{OH}$	Output HIGH Voltage (Note 8)	1450	1530	1575	1525	1565	1600	1550	1590	1625	mV
$V_{OUTPP}$	Output Amplitude Voltage	350	410	525	350	410	525	350	410	525	mV
$V_{IH}$	Input HIGH Voltage (Single-Ended) (Note 10)	$V_{CC} - 1435\text{ mV}$	$V_{CC} - 1000\text{ mV}^*$	$V_{CC}$	$V_{CC} - 1435\text{ mV}$	$V_{CC} - 1000\text{ mV}^*$	$V_{CC}$	$V_{CC} - 1435\text{ mV}$	$V_{CC} - 1000\text{ mV}^*$	$V_{CC}$	V
$V_{IL}$	Input LOW Voltage (Single-Ended) (Note 11)	$V_{IH} - 2.5\text{ V}$	$V_{CC} - 1400\text{ mV}^*$	$V_{IH} - 150\text{ mV}$	$V_{IH} - 2.5\text{ V}$	$V_{CC} - 1400\text{ mV}^*$	$V_{IH} - 150\text{ mV}$	$V_{IH} - 2.5\text{ V}$	$V_{CC} - 1400\text{ mV}^*$	$V_{IH} - 150\text{ mV}$	V
$V_{IHCMR}$	Input HIGH Voltage Common Mode Range (Differential Configuration) (Note 9)	1.2		2.5	1.2		2.5	1.2		2.5	V
$R_{TIN}$	Internal Input Termination Resistor	45	50	55	45	50	55	45	50	55	$\Omega$
$I_{IH}$	Input HIGH Current (@ $V_{IH}$ , $V_{IHMAX}$ )		80	150		80	150		80	150	$\mu\text{A}$
$I_{IL}$	Input LOW Current (@ $V_{IL}$ , $V_{ILMIN}$ )		25	100		25	100		25	100	$\mu\text{A}$

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

\*Typicals used for testing purposes.

\*\*The device packaged in FCBGA-16 have maximum temperature specification of 70°C and devices packaged in QFN-16 have maximum temperature specification of 85°C.

7. Input and output parameters vary 1:1 with  $V_{CC}$ .  $V_{EE}$  can vary +0.125 V to -0.965 V.

8. All loading with 50  $\Omega$  to  $V_{CC} - 1.5\text{ V}$  for BGA package and  $V_{CC} - 2.0\text{ V}$  for QFN package.  $V_{OH}/V_{OL}$  measured at  $V_{IH}/V_{IL}$ .

9.  $V_{IHCMR}$  min varies 1:1 with  $V_{EE}$ ,  $V_{IHCMR}$  max varies 1:1 with  $V_{CC}$ . The  $V_{IHCMR}$  range is referenced to the most positive side of the differential input signal.

10.  $V_{IH}$  cannot exceed  $V_{CC}$ .

11.  $V_{IL}$  always  $\geq V_{EE}$ .

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**Table 6. DC CHARACTERISTICS, INPUT WITH RSPECL OUTPUT**  $V_{CC} = 3.3\text{ V}$ ;  $V_{EE} = 0\text{ V}$  (Note 12)

Symbol	Characteristic	-40°C			25°C			70°C(BGA)/85°C(QFN)**			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
$I_{EE}$	Negative Power Supply Current	45	60	75	45	60	75	45	60	75	mA
$V_{OH}$	Output HIGH Voltage (Note 13)	2250	2330	2375	2325	2365	2400	2350	2390	2425	mV
$V_{OUTPP}$	Output Amplitude Voltage	350	410	525	350	410	525	350	410	525	mV
$V_{IH}$	Input HIGH Voltage (Single-Ended) (Note 15)	$V_{CC} - 1435\text{ mV}$	$V_{CC} - 1000\text{ mV}^*$	$V_{CC}$	$V_{CC} - 1435\text{ mV}$	$V_{CC} - 1000\text{ mV}^*$	$V_{CC}$	$V_{CC} - 1435\text{ mV}$	$V_{CC} - 1000\text{ mV}^*$	$V_{CC}$	V
$V_{IL}$	Input LOW Voltage (Single-Ended) (Note 16)	$V_{IH} - 2.5\text{ V}$	$V_{CC} - 1400\text{ mV}^*$	$V_{IH} - 150\text{ mV}$	$V_{IH} - 2.5\text{ V}$	$V_{CC} - 1400\text{ mV}^*$	$V_{IH} - 150\text{ mV}$	$V_{IH} - 2.5\text{ V}$	$V_{CC} - 1400\text{ mV}^*$	$V_{IH} - 150\text{ mV}$	V
$V_{IHCMR}$	Input HIGH Voltage Common Mode Range (Note 14) (Differential Configuration)	1.2		3.3	1.2		3.3	1.2		3.3	V
$R_{TIN}$	Internal Input Termination Resistor	45	50	55	45	50	55	45	50	55	$\Omega$
$I_{IH}$	Input HIGH Current (@ $V_{IH}$ , $V_{IHMAX}$ )		80	150		80	150		80	150	$\mu\text{A}$
$I_{IL}$	Input LOW Current (@ $V_{IL}$ , $V_{ILMIN}$ )		25	100		25	100		25	100	$\mu\text{A}$

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

12. Input and output parameters vary 1:1 with  $V_{CC}$ .  $V_{EE}$  can vary +0.925 V to -0.165 V.

13. All loading with 50  $\Omega$  to  $V_{CC} - 1.5\text{ V}$  for BGA package and  $V_{CC} - 2.0\text{ V}$  for QFN package.  $V_{OH}/V_{OL}$  measured at  $V_{IH}/V_{IL}$ .

14.  $V_{IHCMR}$  min varies 1:1 with  $V_{EE}$ .  $V_{IHCMR}$  max varies 1:1 with  $V_{CC}$ . The  $V_{IHCMR}$  range is referenced to the most positive side of the differential input signal.

15.  $V_{IH}$  cannot exceed  $V_{CC}$ .

16.  $V_{IL}$  always  $\geq V_{EE}$ .

\*Typicals used for testing purposes.

\*\*The device packaged in FCBGA-16 have maximum temperature specification of 70°C and devices packaged in QFN-16 have maximum temperature specification of 85°C.

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**Table 7. DC CHARACTERISTICS, NECL OR RSNECL INPUT WITH NECL OUTPUT**

$V_{CC} = 0\text{ V}$ ;  $V_{EE} = -3.465\text{ V}$  to  $-2.375\text{ V}$  (Note 17)

Symbol	Characteristic	-40°C			25°C			70°C(BGA)/85°C(QFN)**			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
$I_{EE}$	Negative Power Supply Current	45	60	75	45	60	75	45	60	75	mA
$V_{OH}$	Output HIGH Voltage (Note 18)	-1050	-970	-925	-975	-935	-900	-950	-910	-875	mV
$V_{OUTPP}$	Output Amplitude Voltage	350	410	525	350	410	525	350	410	525	mV
$V_{IH}$	Input HIGH Voltage (Single-Ended) (Note 20)	$V_{CC}-1435\text{ mV}$	$V_{CC}-1000\text{ mV}^*$	$V_{CC}$	$V_{CC}-1435\text{ mV}$	$V_{CC}-1000\text{ mV}^*$	$V_{CC}$	$V_{CC}-1435\text{ mV}$	$V_{CC}-1000\text{ mV}^*$	$V_{CC}$	V
$V_{IL}$	Input LOW Voltage (Single-Ended) (Note 21)	$V_{IH}-2.5\text{ V}$	$V_{CC}-1400\text{ mV}^*$	$V_{IH}-150\text{ mV}$	$V_{IH}-2.5\text{ V}$	$V_{CC}-1400\text{ mV}^*$	$V_{IH}-150\text{ mV}$	$V_{IH}-2.5\text{ V}$	$V_{CC}-1400\text{ mV}^*$	$V_{IH}-150\text{ mV}$	V
$V_{IHCMR}$	Input HIGH Voltage Common Mode Range (Differential Configuration) (Note 19)	$V_{EE}+1.2$		0.0	$V_{EE}+1.2$		0.0	$V_{EE}+1.2$		0.0	V
$R_{TIN}$	Internal Input Termination Resistor	45	50	55	45	50	55	45	50	55	$\Omega$
$I_{IH}$	Input HIGH Current (@ $V_{IH}$ , $V_{IHMAX}$ )		80	150		80	150		80	150	$\mu\text{A}$
$I_{IL}$	Input LOW Current (@ $V_{IL}$ , $V_{ILMIN}$ )		25	100		25	100		25	100	$\mu\text{A}$

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

17. Input and output parameters vary 1:1 with  $V_{CC}$ .

18. All loading with  $50\ \Omega$  to  $V_{CC} - 1.5\text{ V}$  for BGA package and  $V_{CC} - 2.0\text{ V}$  for QFN package.  $V_{OH}/V_{OL}$  measured at  $V_{IH}/V_{IL}$ .

19.  $V_{IHCMR}$  min varies 1:1 with  $V_{EE}$ ,  $V_{IHCMR}$  max varies 1:1 with  $V_{CC}$ . The  $V_{IHCMR}$  range is referenced to the most positive side of the differential input signal.

20.  $V_{IH}$  cannot exceed  $V_{CC}$ .

21.  $V_{IL}$  always  $\geq V_{EE}$ .

\*Typicals used for testing purposes.

\*\*The device packaged in FCBGA-16 have maximum temperature specification of 70°C and devices packaged in QFN-16 have maximum temperature specification of 85°C.

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**Table 8. AC CHARACTERISTICS for FCBGA-16**

$V_{CC} = 0\text{ V}$ ;  $V_{EE} = -3.465\text{ V}$  to  $-2.375\text{ V}$  or  $V_{CC} = 2.375\text{ V}$  to  $3.465\text{ V}$ ;  $V_{EE} = 0\text{ V}$

Symbol	Characteristic	-40°C			25°C			70°C			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
$f_{max}$	Maximum Frequency (See Figure 4. $F_{max}/JITTER$ ) (Note 22)	10.709	12		10.709	12		10.709	12		GHz
$t_{PLH}$ , $t_{PHL}$	Propagation Delay to Output Differential	90	125	160	90	125	160	90	125	160	ps
$t_{SKEW}$	Duty Cycle Skew (Note 23) Within-Device Skew (Note 24) Device-to-Device Skew (Note 25)		3 6 25	15 15 50		3 6 25	15 15 50		3 6 25	15 15 50	ps
$t_{JITTER}$	RMS Random Clock Jitter $f_{in} < 10\text{ GHz}$ Peak-to-Peak Data Dependent Jitter $f_{in} < 10\text{ Gb/s}$		0.2 10	1		0.2 10	1		0.2 10	1	ps
$V_{INPP}$	Input Voltage Swing/Sensitivity (Differential Configuration) (Note 26)	75		2600	75		2600	75		2600	mV
$t_r$ $t_f$	Output Rise/Fall Times (20% – 80%) @ 1 GHz	20	30	55	20	30	55	20	30	55	ps

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

22. Measured using a 500 mV source, 50% duty cycle clock source. All loading with  $50\ \Omega$  to  $V_{CC} - 1.5\text{ V}$  for BGA package. For minimum  $f_{max}$  value of 10.709 GHz, output amplitude is approximately 200 mV (as shown in Figure 4, where output P-P spec is shown as a minimum/guarantee of around 150 mV). Input edge rates 40 ps (20% – 80%).

23. See Figure 5.  $t_{SKEW} = |t_{PLH} - t_{PHL}|$  for a nominal 50% Differential Clock Input Waveform.

24. Within-Device skew is defined as identical transitions on similar paths through a device.

25. Device-to-device skew for identical transitions at identical  $V_{CC}$  levels.

26.  $V_{INPP}$  (MAX) cannot exceed  $V_{CC} - V_{EE}$ .



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**Table 9. AC CHARACTERISTICS for QFN-16**  $V_{CC} = 0\text{ V}$ ;  $V_{EE} = -3.465\text{ V}$  to  $-2.375\text{ V}$  or  $V_{CC} = 2.375\text{ V}$  to  $3.465\text{ V}$ ;  $V_{EE} = 0\text{ V}$

Symbol	Characteristic	-40°C			25°C			85°C			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
$f_{max}$	Maximum Frequency (See Figure 4. $F_{max}/JITTER$ ) (Note 27)	10.5	12		10.5	12		10.5	12		GHz
$t_{PLH}$ , $t_{PHL}$	Propagation Delay to Output Differential	90	125	160	90	125	160	90	125	160	ps
$t_{SKEW}$	Duty Cycle Skew (Note 28) Within-Device Skew (Note 29) Device-to-Device Skew (Note 30)		3 6 25	15 15 50		3 6 25	15 15 50		3 6 25	15 15 50	ps
$t_{JITTER}$	RMS Random Clock Jitter $f_{in} < 10\text{ GHz}$ Peak-to-Peak Data Dependent Jitter $f_{in} < 10\text{ Gb/s}$		0.2 10.7	1		0.2 10.7	1		0.2 10.7	1	ps
$V_{INPP}$	Input Voltage Swing/Sensitivity (Differential Configuration) (Note 31)	75		2600	75		2600	75		2600	mV
$t_r$ , $t_f$	Output Rise/Fall Times (20% - 80%) @ 1 GHz	15	30	55	20	30	55	20	30	55	ps

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

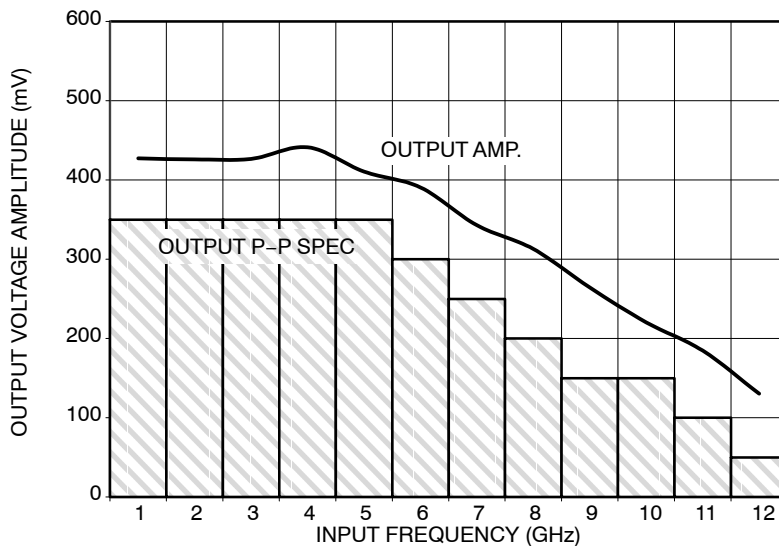
27. Measured using a 500 mV source, 50% duty cycle clock source. All loading with  $50\ \Omega$  to  $V_{CC} - 2.0\text{ V}$  for QFN package. For minimum  $f_{max}$  value of 10.5 GHz, output amplitude is approximately 200 mV (as shown in Figure 4, where output P-P spec is shown as a minimum/guarantee of around 150 mV). Input edge rates 40 ps (20% - 80%).

28. See Figure 5.  $t_{SKEW} = |t_{PLH} - t_{PHL}|$  for a nominal 50% Differential Clock Input Waveform.

29. Within-Device skew is defined as identical transitions on similar paths through a device.

30. Device-to-device skew for identical transitions at identical  $V_{CC}$  levels.

31.  $V_{INPP}$  (MAX) cannot exceed  $V_{CC} - V_{EE}$ .



**Figure 4. Output Amplitude ( $V_{OUTPP}$ ) vs. Input Frequency ( $F_{IN}$ ) at Ambient Temperature (Typical)**

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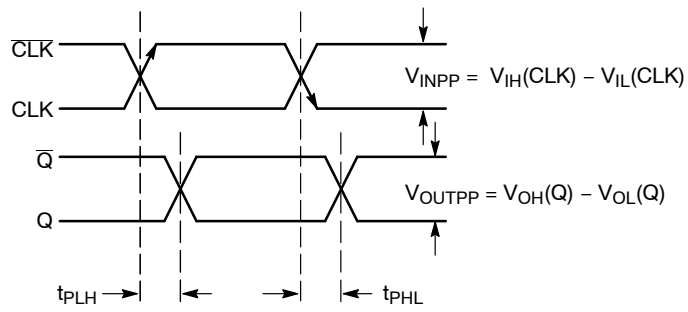


Figure 5. AC Reference Measurement

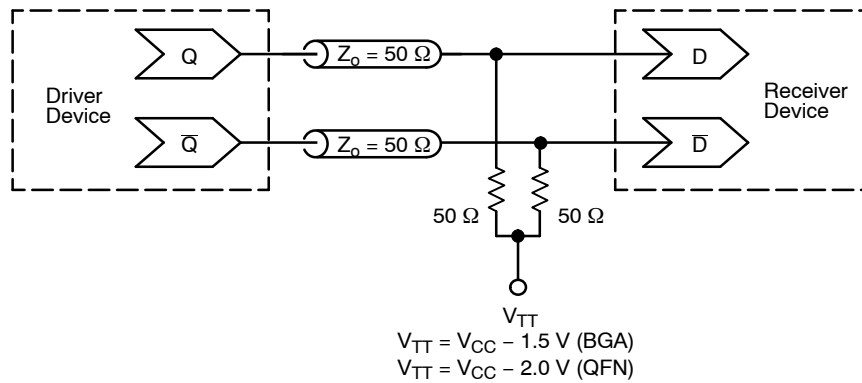


Figure 6. Typical Termination for Output Driver and Device Evaluation (See Application Note AND8020/D – Termination of ECL Logic Devices.)

## ORDERING INFORMATION

Device	Package	Shipping <sup>†</sup>
NBSG11BAHTBG	FCBGA-16 (Pb-Free)	100 / Tape & Reel
NBSG11BAR2	FCBGA-16	100 / Tape & Reel (Contact Sales Representative)
NBSG11MN	QFN-16	123 Units / Rail
NBSG11MNG	QFN-16 (Pb-Free)	123 Units / Rail
NBSG11MNR2	QFN-16	3000 / Tape & Reel
NBSG11MNR2G	QFN-16 (Pb-Free)	3000 / Tape & Reel
NBSG11MNHTBG	QFN-16 (Pb-Free)	100 / Tape & Reel

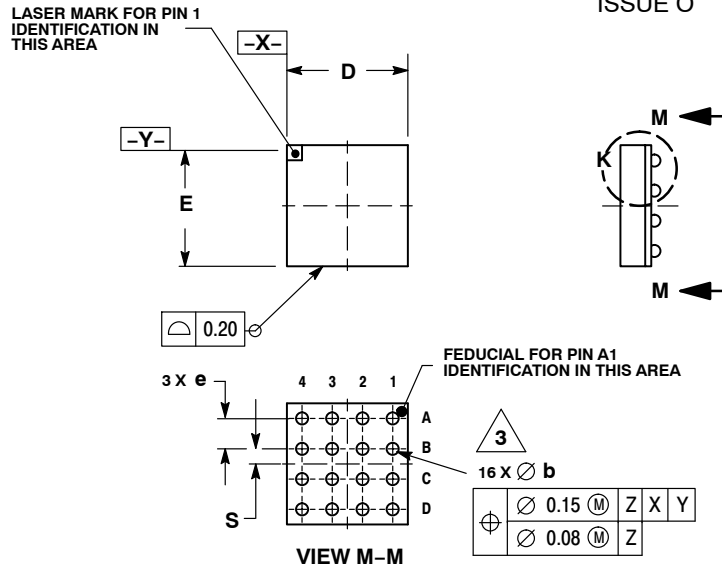
Board	Description
NBSG11BAEVB	NBSG11BA Evaluation Board

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

# NBSG11

## PACKAGE DIMENSIONS

**FCBGA-16**  
**BA SUFFIX**  
 PLASTIC 4X4 (mm) BGA FLIP CHIP PACKAGE  
 CASE 489-01  
 ISSUE O



**NOTES:**

1. DIMENSIONS ARE IN MILLIMETERS.
2. INTERPRET DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994.
3. DIMENSION b IS MEASURED AT THE MAXIMUM SOLDER BALL DIAMETER, PARALLEL TO DATUM PLANE Z.
4. DATUM Z (SEATING PLANE) IS DEFINED BY THE SPHERICAL CROWNS OF THE SOLDER BALLS.
5. PARALLELISM MEASUREMENT SHALL EXCLUDE ANY EFFECT OF MARK ON TOP SURFACE OF PACKAGE.

DIM	MILLIMETERS	
	MIN	MAX
A	1.40	MAX
A1	0.25	0.35
A2	1.20	REF
b	0.30	0.50
D	4.00	BSC
E	4.00	BSC
e	1.00	BSC
S	0.50	BSC

16 X	Ø b				
⊕	Ø 0.15	(M)	Z	X	Y
	Ø 0.08	(M)	Z		

3

0.15 Z

4

0.10 Z

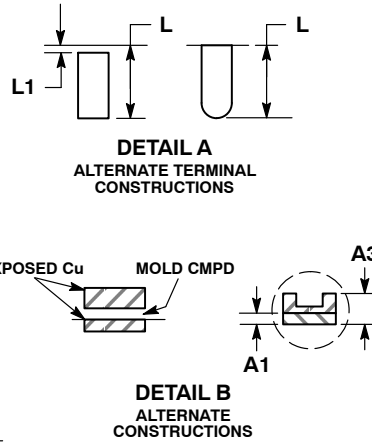
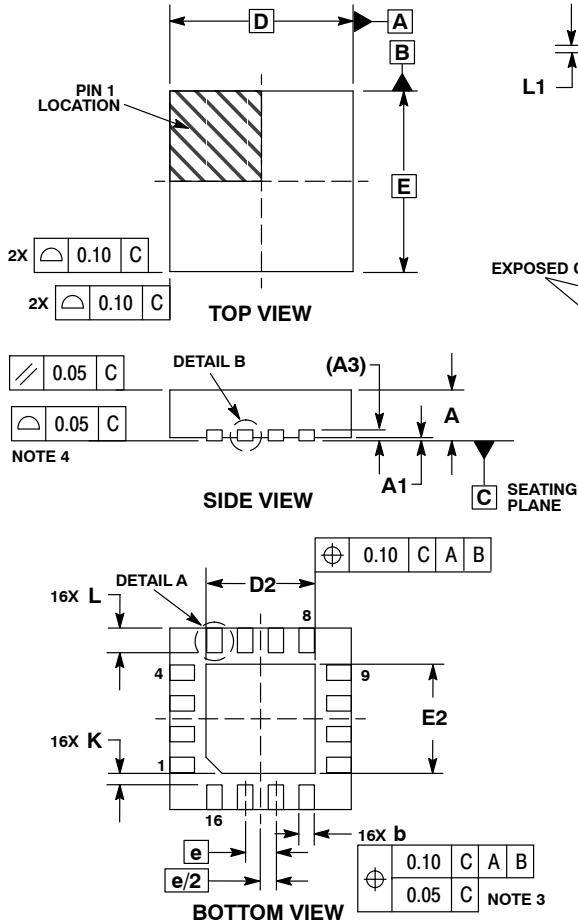
16 X

-Z-

# NBSG11

## PACKAGE DIMENSIONS

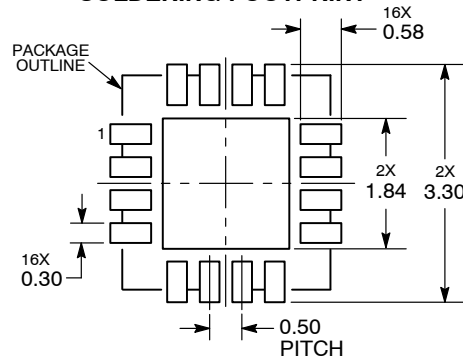
QFN16 3x3, 0.5P  
CASE 485G-01  
ISSUE E



- NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
  2. CONTROLLING DIMENSION: MILLIMETERS.
  3. DIMENSION b APPLIES TO PLATED TERMINAL AND IS MEASURED BETWEEN 0.25 AND 0.30 MM FROM TERMINAL.
  4. COPLANARITY APPLIES TO THE EXPOSED PAD AS WELL AS THE TERMINALS.

DIM	MILLIMETERS	
	MIN	MAX
A	0.80	1.00
A1	0.00	0.05
A3	0.20	REF
b	0.18	0.30
D	3.00	BSC
D2	1.65	1.85
E	3.00	BSC
E2	1.65	1.85
e	0.50	BSC
K	0.18	TYP
L	0.30	0.50
L1	0.00	0.15

### RECOMMENDED SOLDERING FOOTPRINT\*



DIMENSIONS: MILLIMETERS

\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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